

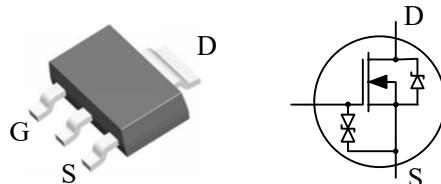
850V Depletion-Mode Power MOSFET

General Features

- Depletion Mode (Normally On)
- ESD Improved Capability
- Fast Switching Speed
- RoHS Compliant
- Halogen-free Available

BV_{DSX}	$R_{DS(ON)(TYP.)}$	I_{DSS}
850V	50 Ω	80mA

SOT-223



Applications

- Normally-On Switches
- Start-up Circuits
- Protection Circuits
- Solid State Relays
- Power Supply
- Active Loads

Ordering Information

Part Number	Package	Marking	Remark
DMS8550E	SOT-223	8550	Halogen Free

Absolute Maximum Ratings

 $T_A=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	DMS8550E	Unit
V_{DSX}	Drain-to-Source Voltage [1]	850	V
I_D	Continuous Drain Current	80	mA
I_{DM}	Pulsed Drain Current [2]	320	
P_D	Power Dissipation	1.5	W
V_{GS}	Gate-to-Source Voltage	± 20	V
T_L	Soldering Temperature Distance of 1.6mm from case for 10 seconds	300	°C
T_J and T_{STG}	Operating and Storage Temperature Range	-55 to 150	

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Characteristics

Symbol	Parameter	DMS8550E	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	83	K/W



Electrical Characteristics

OFF Characteristics

T_A = 25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
BV _{DSX}	Drain-to-Source Breakdown Voltage	850	--	--	V	V _{GS} =-10V, I _D =250μA
I _{D(OFF)}	Drain-to-Source Leakage Current	--	--	10	μA	V _{DS} =850V, V _{GS} =-10V
I _{GSS}	Gate-to-Source Leakage Current	--	--	±20	uA	V _{GS} =±20V, V _{DS} =0V

ON Characteristics

T_A = 25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
I _{DSS}	Saturated Drain-to-Source Current	80	--	--	mA	V _{GS} =0V, V _{DS} =25V
R _{D(S(ON))}	Static Drain-to-Source On-Resistance	--	50	80	Ω	V _{GS} =0V, I _D =50mA [3]
V _{GS(OFF)}	Gate-to-Source Cut-off Voltage	-1.5	--	-3.3	V	V _{DS} =9V, I _D =8μA
g _{fs}	Forward Transconductance	--	--	--	S	V _{DS} =20V, I _D =50mA

Dynamic Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
C _{iss}	Input Capacitance	--	--	--	pF	V _{GS} =-10V V _{DS} =50V f=1.0MHz
C _{oss}	Output Capacitance	--	--	--		
C _{rss}	Reverse Transfer Capacitance	--	--	--		
Q _g	Total Gate Charge	--	--	--	nC	V _{GS} =-10V~5V V _{DS} =150V, I _D =50mA
Q _{gs}	Gate-to-Source Charge	--	--	--		
Q _{gd}	Gate-to-Drain (Miller) Charge	--	--	--		

Resistive Switching Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
t _{d(on)}	Turn-on Delay Time	--	--	--	ns	V _{GS} =-10V~0V V _{DD} =50V, I _D =50mA R _G =10Ω
t _{rise}	Rise Time	--	--	--		
t _{d(off)}	Turn-off Delay Time	--	--	--		
t _{fall}	Fall Time	--	--	--		



DMS8550E

Provisional Datasheet

Source-Drain Diode Characteristics

T_A=25°C unless otherwise specified

Symbol	Parameter	Min	Typ.	Max.	Units	Test Conditions
V _{SD}	Diode Forward Voltage	--	--	1.2	V	I _{SD} =50mA, V _{GS} =-10V

NOTE:

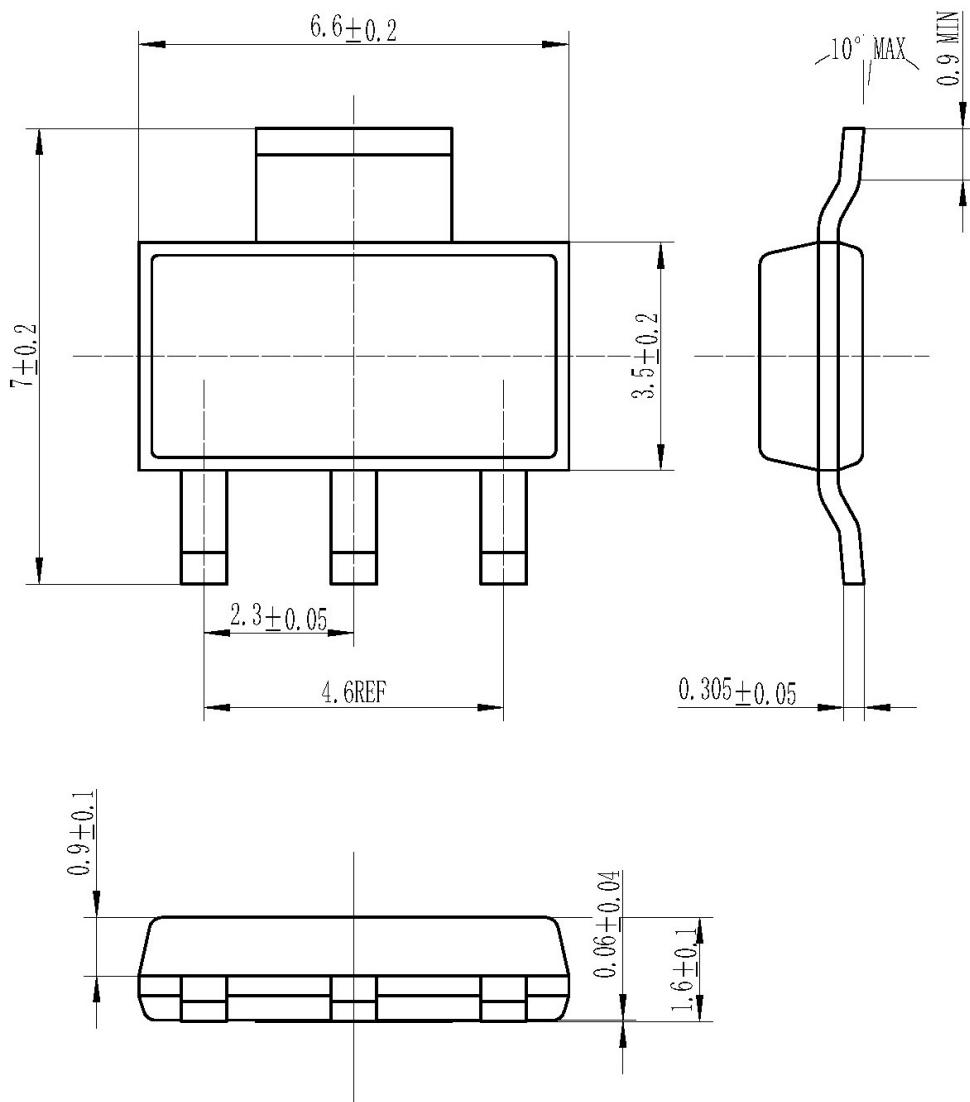
[1] T_J=+25°C to +150°C

[2] Repetitive rating, pulse width limited by maximum junction temperature.

[3] Pulse width≤380μs; duty cycle≤2%.

Package Dimensions

TO-223





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